

Studies on Al: Zn₂SnO₄ TCO layers for PV application

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Al doped zinc stannate (Al:Zn₂SnO₄) has attracted much attention as a next well generation TCO due to its abundance, non-toxicity, high stability, and cost effective nature as well as good opto-electrical properties [1]. In this work, Al:Zn₂SnO₄ layers were co-sputtered on glass substrates using three inches SnO₂ (4N purity) and Al:ZnO (4N purity) targets by RF and DC magnetron sputtering. All the prepared AZTO layers showed good uniformity and adherence. The full scan XPS spectrum of the layers showed the peaks of Zn 2p, Sn 3d, O 1s and Al 2p, which confirmed the presence of Zn, Sn, O and Al elements in the films. In addition, there were no other elementary impurities in the layers. The high resolution XPS spectra of Zn 2p, Sn 3d, O 1s and Al 2p revealed that the binding energies of Zn 2p_{3/2} and Zn 2p_{1/2}; Sn 3d_{5/2} and Sn 3d_{3/2}; O 1s; and Al 2p are at 1022.1 eV and 1045.1 eV; 486.5 eV and 495.3 eV; 530.4 eV and 73.8 eV, respectively. The layer had an average transmittance of over 80%, energy band gap of > 3.5 eV and the lower electrical resistivity of $1.29 \times 10^{-1} \Omega \text{ cm}$. The exhibited properties of Al: Zn₂SnO₄ layers made them suitable for making good TCO for photovoltaic and optoelectronic applications.